Search Notes							
							ı

Application/Control	No.
•	

Applicant(s)/Patent under Reexamination

10/706,749

FURUYA ET AL. Art Unit

Examiner

2627

Matthew G. Kayrish

	SEAR	CHED	
Class	Subclass	Date	Examiner
720	675	7/14/2006	мк

ERFERENC	ERENCE SEARCHED		
Subclass	Date	Examiner	
<u> </u>			
	<u> </u>	Subclass Date	

SEARCH NOT (INCLUDING SEARCH		<u> </u>
	DATE	EXMR
EAST (USPG-PUB, USPAT, USOCR, EPO, JPO, IBM_TDB, DERWENT) (See Attached Search History)	7/14/2006	MK